

Notice of References Cited	Application/Control No. 10/628,276	Applicant(s)/Patent Under Reexamination KANG ET AL.	
	Examiner Mark A. Williams	Art Unit 3676	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,799,371	09-1998	Lin, Jim	16/330
	B	US-6,175,990 B1	01-2001	Kato et al.	16/334
	C	US-5,106,354 A	04-1992	Russ et al.	475/342
	D	US-2004/0107537 A1	06-2004	Ahn et al.	016/221
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	KR 2002035553 A	05-2002	Korea, Republic	LEE, H S	H04B 01/38
	O	JP 2003198664 A	07-2003	Japan	YAMAMURA et al.	H04M 01/00
	P	JP 2004015606 A	01-2004	Japan	KOBAYASHI, FUMIYUKI	H04M 01/00
	Q	JP 2003056545 A	02-2003	Japan	TAKAHASHI, ATSUSHI	F16C 11/04
	R	JP 2004064119 A	02-2004	Japan	SHIMIZU et al.	H04M 01/02
	S	JP 2001203763 A	07-2001	Japan	NAKAMURA, TAKUJI	H04L 25/02
	T	JP 2004052895 A	02-2004	Japan	HAYASHI, MINORU	F16C 11/10

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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